

Freeform Advances at Optimax: Manufacturing and Measurement

Presented By:

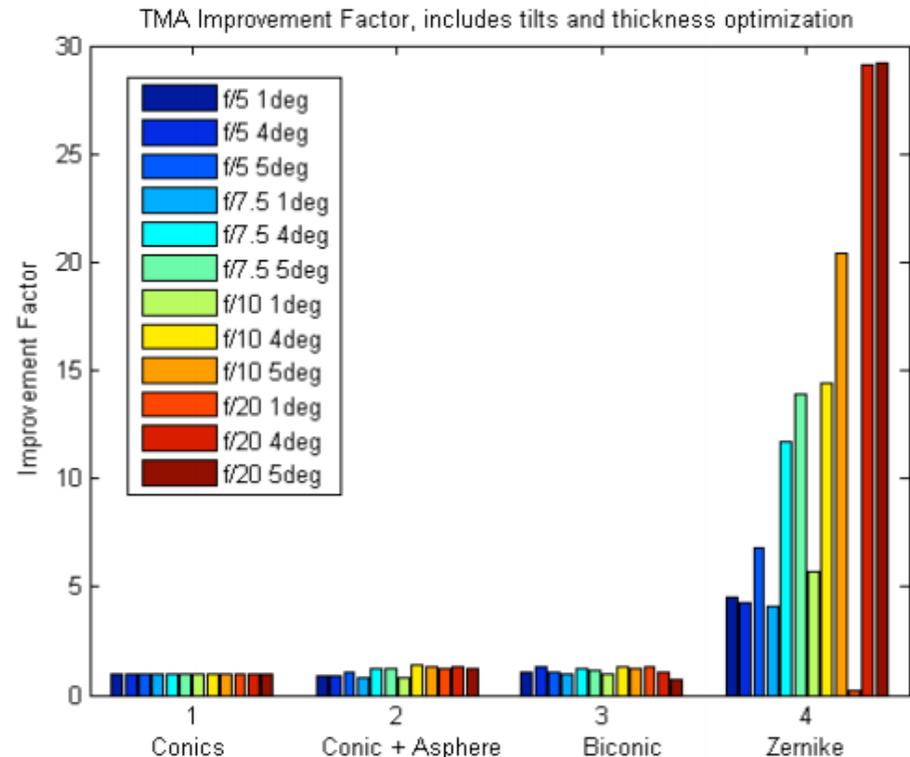
Todd Blalock, Kate Medicus, Brian Myer,
Jessica DeGroot Nelson

Freeforms are desirable optical components

- Lighter weight
- Reduced number of components
- Reduced aberrations



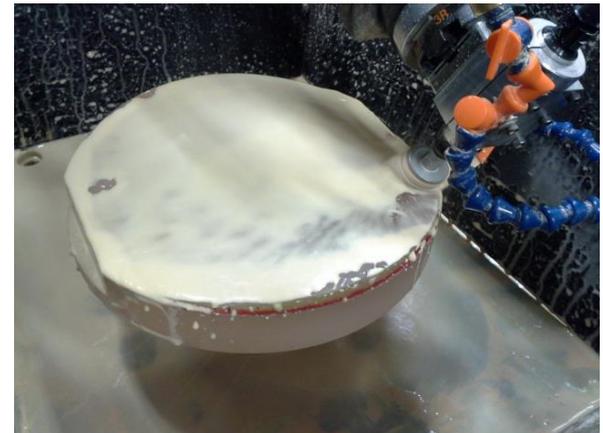
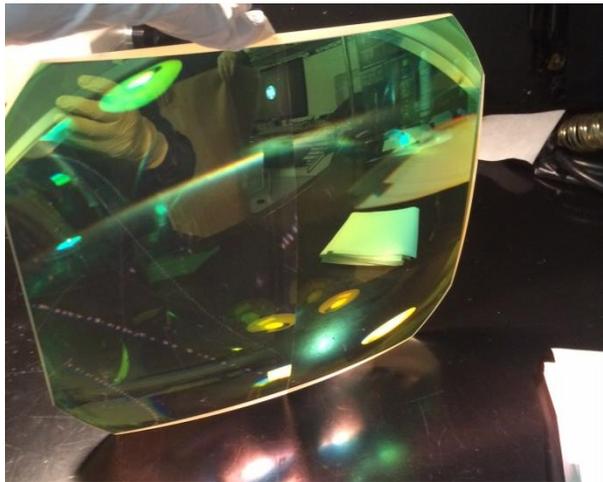
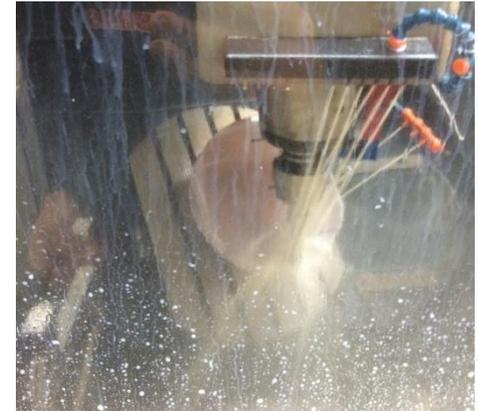
- Off-axis asphere
- Toroids, biconics
- Polynomial functions
- Anamorphic equations
- Zernikes
- Other equation based models
- Solid models



J M Howard and S Wolbach, "Improving the performance of three-mirror imaging systems with Freeform Optics," OSA Freeform Optics Conference, November 2013

Freeforms are now a product offering at Optimax

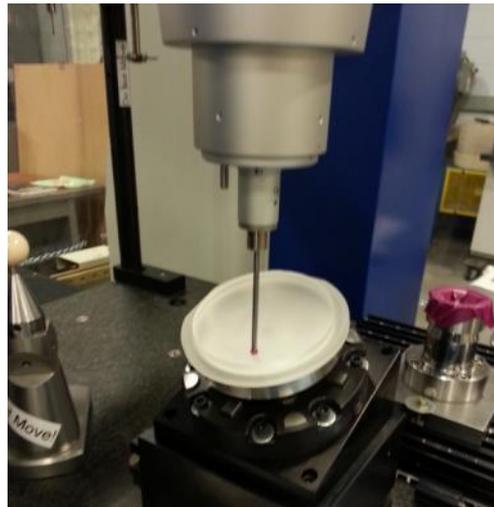
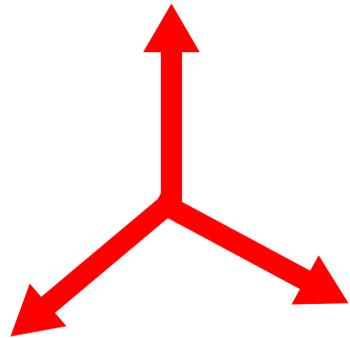
- As of January 2015, freeform optics are a standard product offering for Optimax
- Uses much of the SBIR developed technology
- Many different shapes and sizes
- Optics are current being used by customers in their optical systems



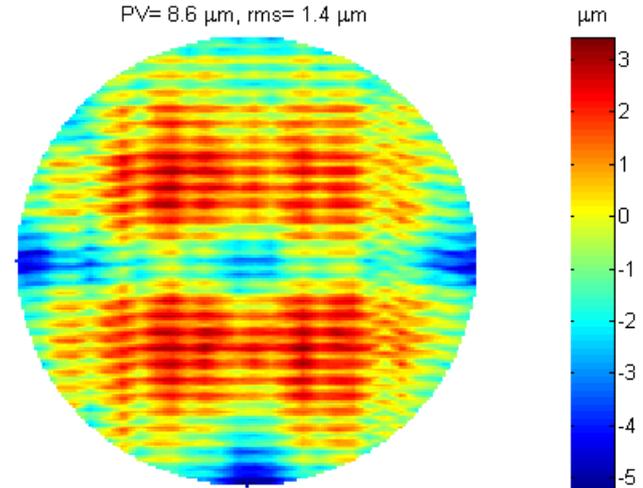
Challenges in Freeform Manufacturing

What makes freeform manufacturing hard?

- Machine control and access
- Coordinate system referencing
- Measurements
- Mid-spatial frequency errors



Post Generation
PV= 8.6 μm , rms= 1.4 μm



Challenges: The Platform

- Robotic deterministic polishing platform
- Developed specifically to address challenges associated with manufacturing of freeform optics
- Uses a dwell-based correction algorithms
- The flexibility of the platform allows us to lap, polish, and smooth parts all on one machine



Challenges: The Platform

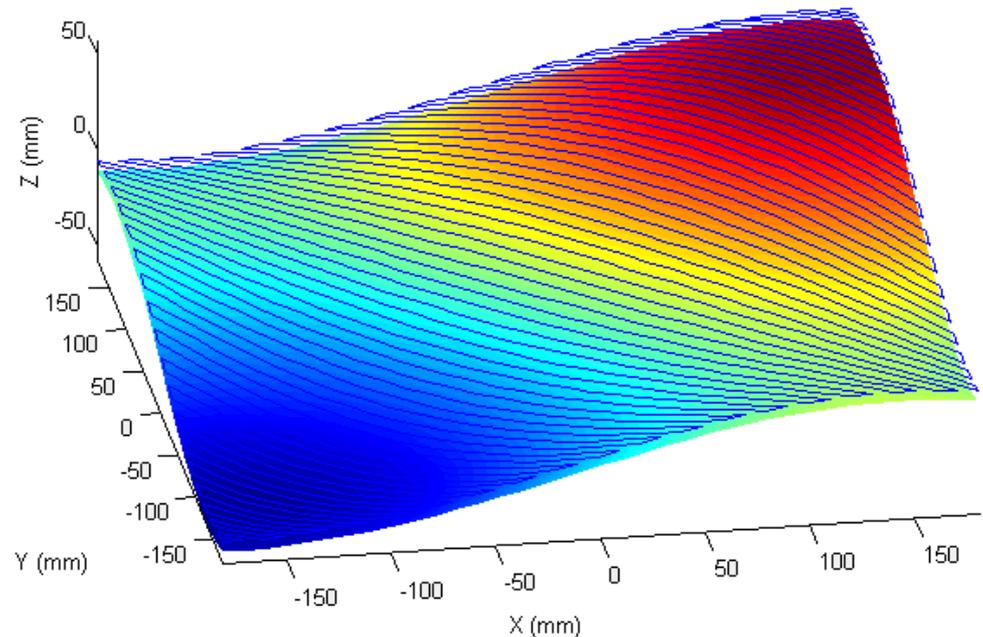
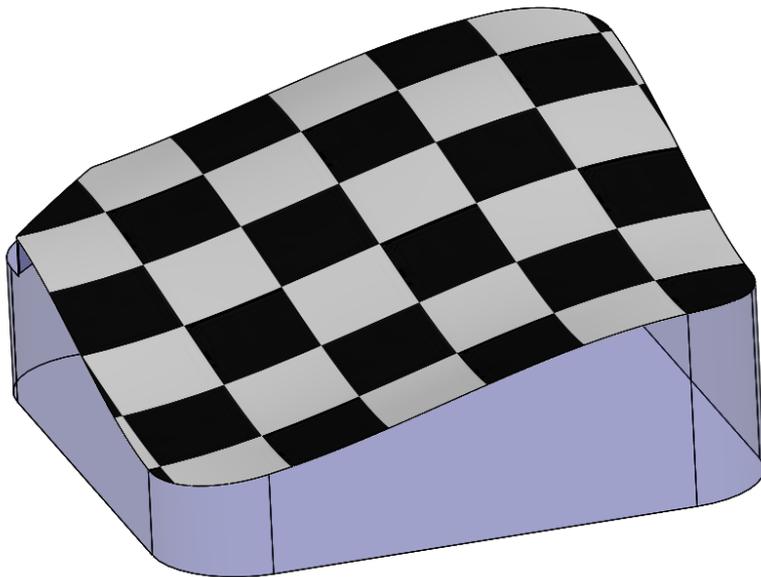
- High torque tooling spindle
- Integrated touch probe capabilities
- Custom machine base with both stationary and precision rotary mounts



Challenges: The Platform

In-house software development gives us the flexibility to work with unique freeform geometries

All software development is done in-house and can be customized to account for a variety of complex surface definitions



Challenges: The Platform

The robotic platform gives us the flexibility to accurately track along unique freeform geometries



Challenges: Mid-spatial Frequency Error

- Because freeforms are made using sub-aperture polishing, mid-spatial frequency error is likely
- Compliant full aperture polishing can be used to smooth the MSF errors

SN1: Not smoothed



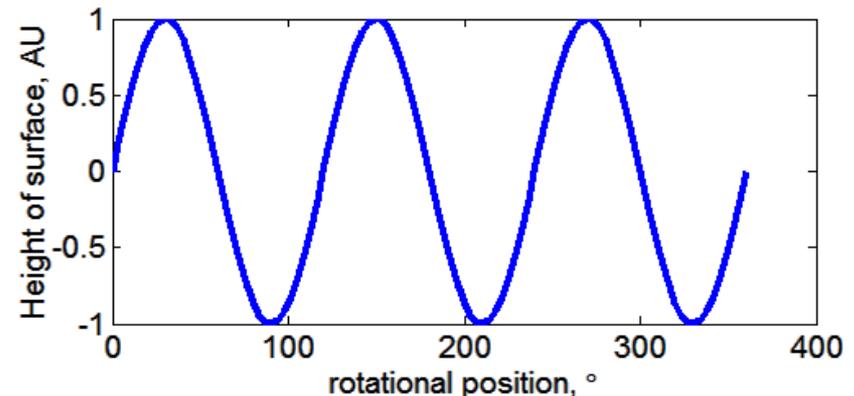
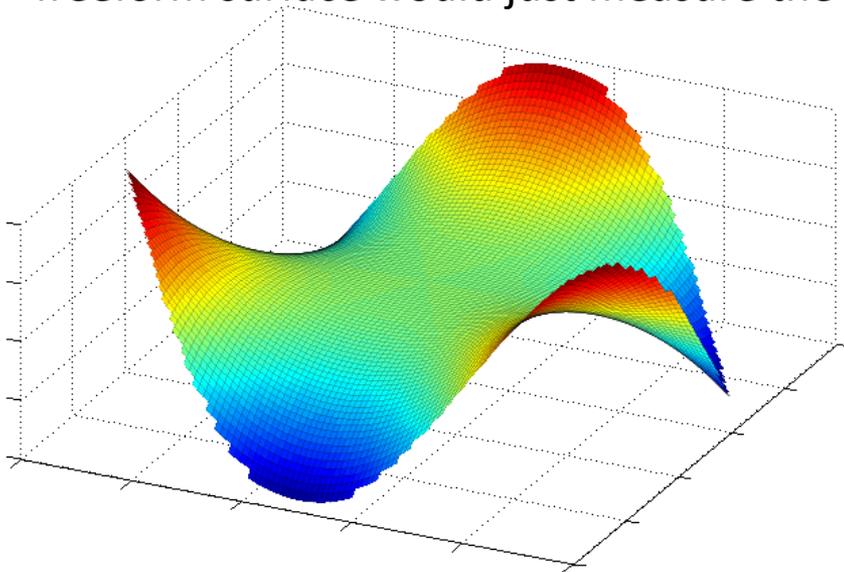
SN2: Smoothed



Challenges: Coordinate System Referencing

With freeform surfaces, there is no clear method to reference the location of the freeform surface relative to the other surfaces on the optic.

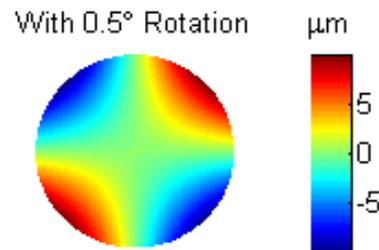
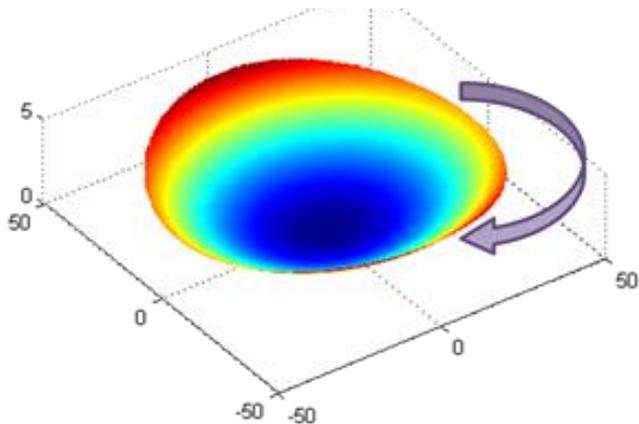
Wedge Example: Placing an indicator on the edge of a freeform surface would just measure the nominal shape



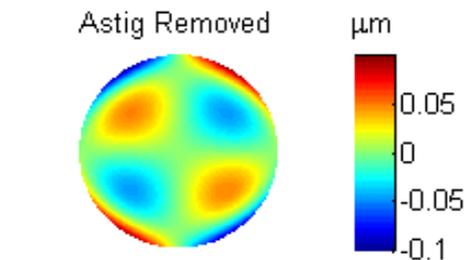
Challenges: Coordinate System Referencing

Also, it is difficult to separate out form error from misalignment in measurement due to incorrect coordinate system referencing

- A 0.5° rotational error in measurements
- 100 mm diameter biconic
- Error is $19\ \mu\text{m}$ PV astigmatism and $0.2\ \mu\text{m}$ higher order error



$19\ \mu\text{m}$ PV, $3.9\ \mu\text{m}$ rms

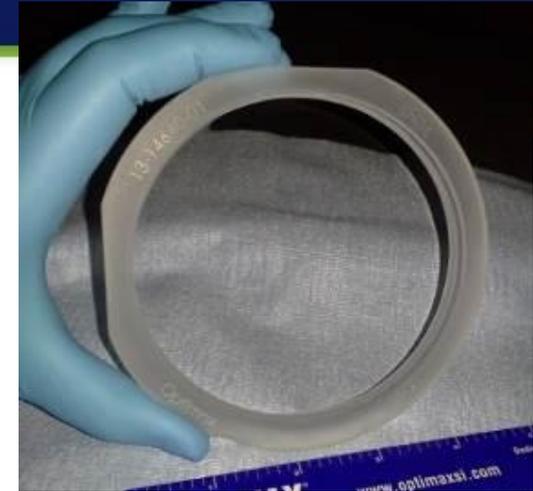


$0.2\ \mu\text{m}$ PV, $0.03\ \mu\text{m}$ rms

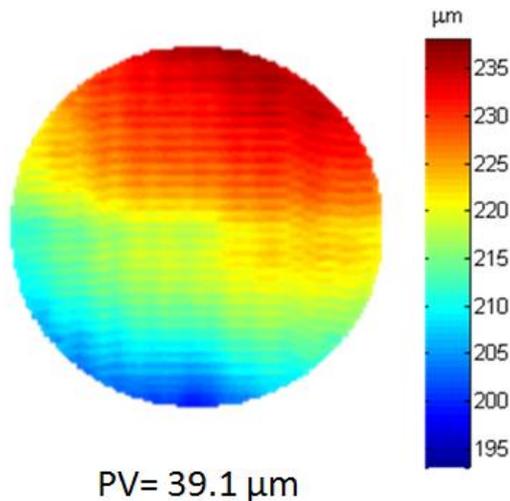
$R_x = 333.5\ \text{mm}$, $k_x = 1.1$, $R_y = 243.50\ \text{mm}$, $k_y = 1.3$

Challenges: Coordinate System Referencing

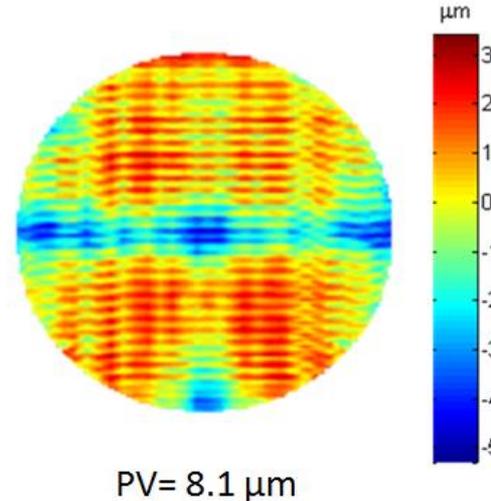
Freeforms should be manufactured with fiducials to clearly define the part coordinate system for manufacturing and measurement



Measured Relative to the X,Y,Z Fiducials



Measured Best Fit to the Surface



Concave biconic

Z-offset shows the part is thick

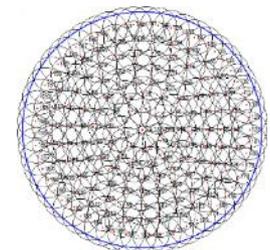
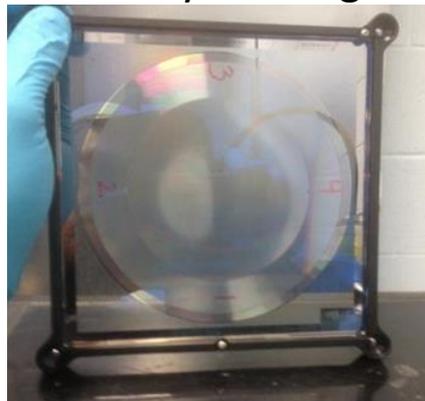
Challenges: Measurement of freeform surfaces

Point/Trace Methods

- Traditional tactile probe scanning coordinate measuring machines: CMMs
- Non-traditional CMMs with rotation axes and optical non-contact probes
- Profile measurements

Interferometric Methods

- Computer generated holograms, CGHs
- Straight shot interferometer is possible when slope of freeform departure from a best fit sphere is small ($< \sim 30 \mu\text{m}$)
- Sub-aperture stitching interferometry is being developed for freeforms

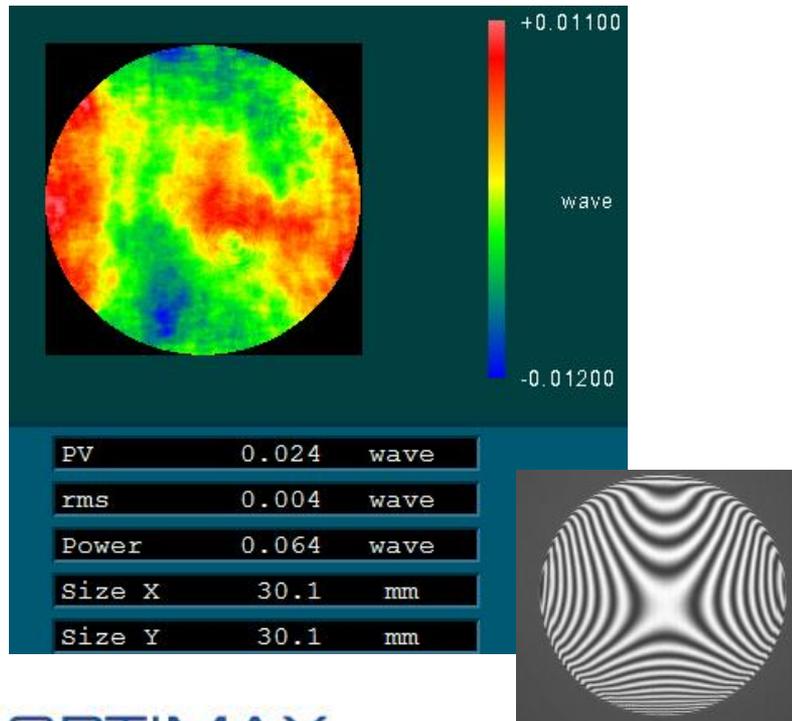


Measurement method dictates achievable form error (irregularity)

- Interferometric Example

- Off-axis parabola (OAP)

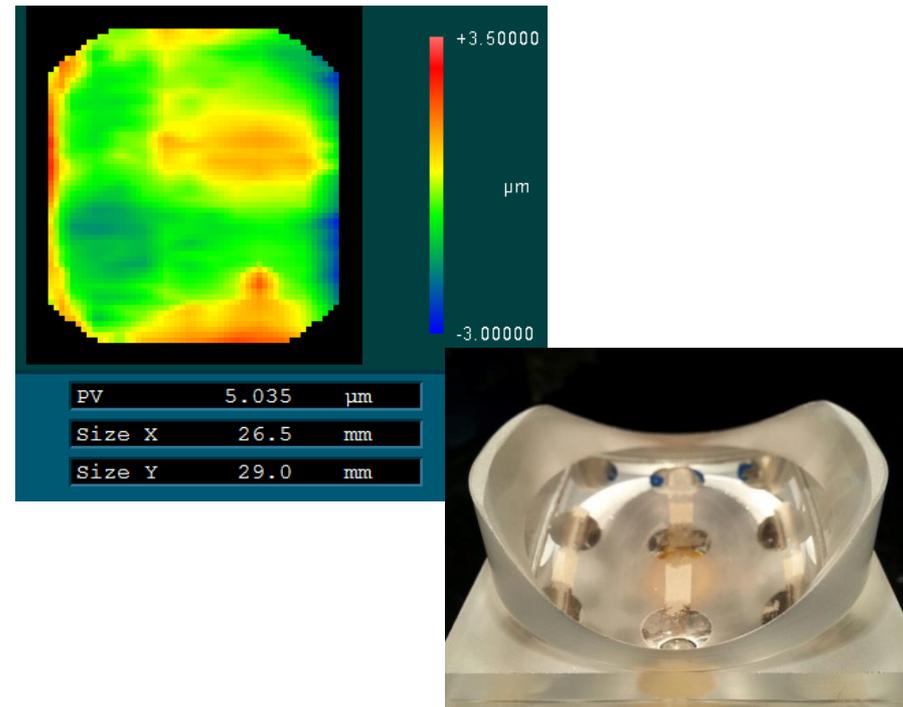
- 30 mm CA
- $\lambda/40$ PV irregularity



- CMM Example

- Anamorph

- 26 x 29 mm CA
- 5 μm PV irregularity

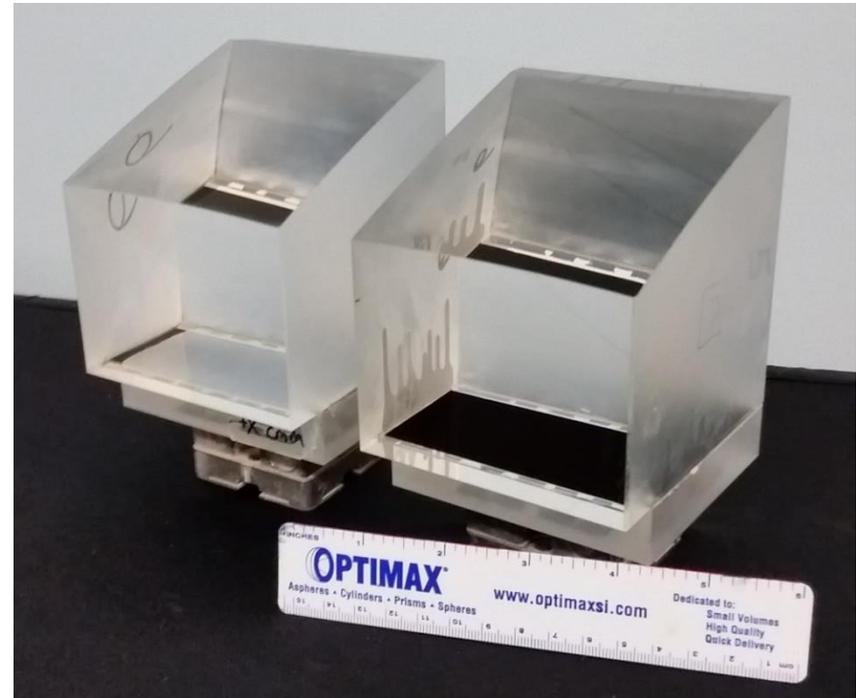


Development Projects

Manufacturing Monolithic Freeform Optics

Freeform Measurements:

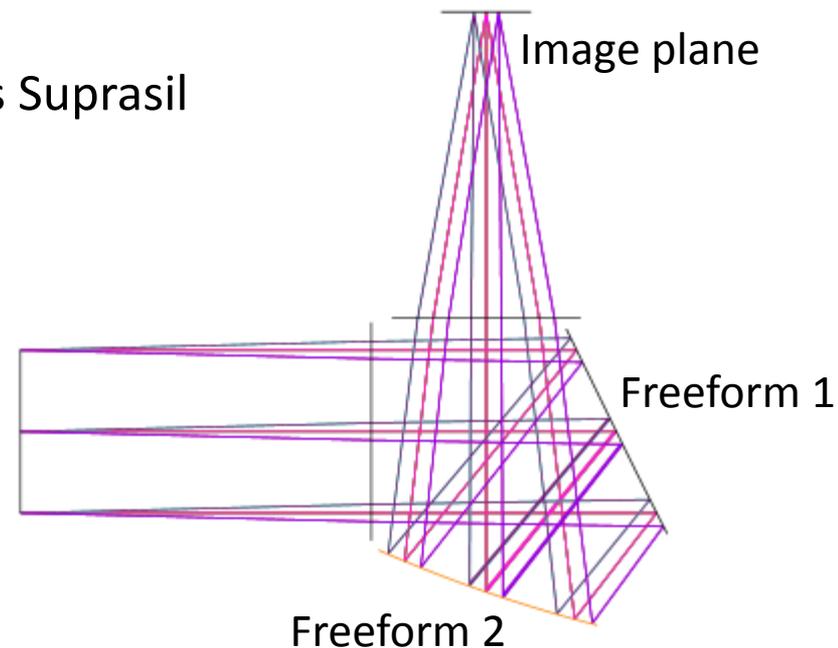
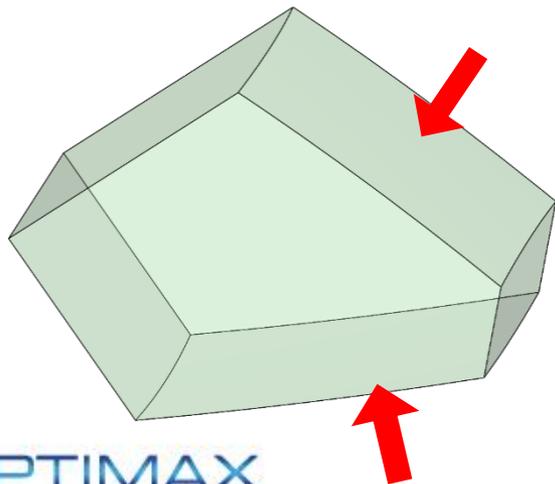
- Self Referencing Referenced Single Point Probing
- Fringe Reflection Deflectometry



Development Project: Multi Surface Freeform Monolithic Optic

Monolithic optics have promise to reduce assembly need and improve stability

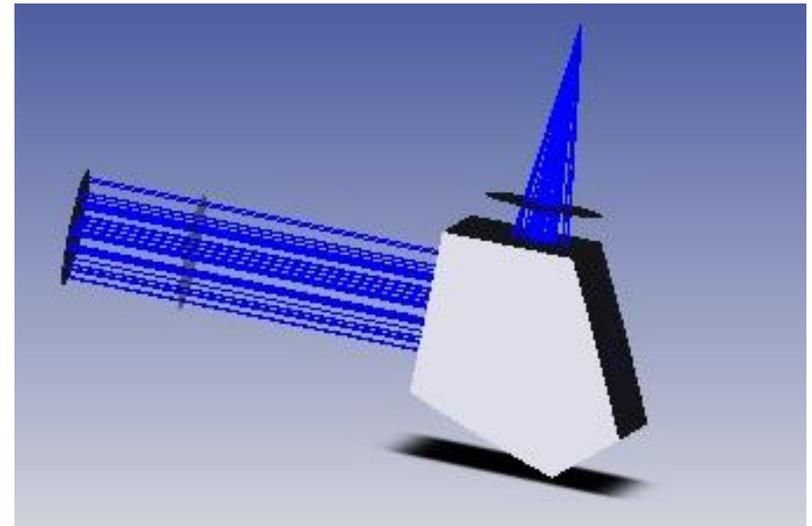
- Four surface: two plano, two freeform
- Plano surfaces are used to create a fixed coordinate system
- About 100 mm cubed
- Fused Silica
 - One of standard quality
 - One of extremely high quality Heraeus Suprasil



Multi Surface Freeform Monolithic Optic

- Freeform surfaces defined with polynomial X,Y function up to 4th order
- Surface deviations from a best fit sphere is 120 μm and 130 μm

$$Z = AX + BY + CX^2 + DXY + EY^2 + FX^3 + GX^2Y + HXY^2 + IY^3 + JX^4 + KX^3Y + LX^2Y^2 + MXY^3 + NY^4$$

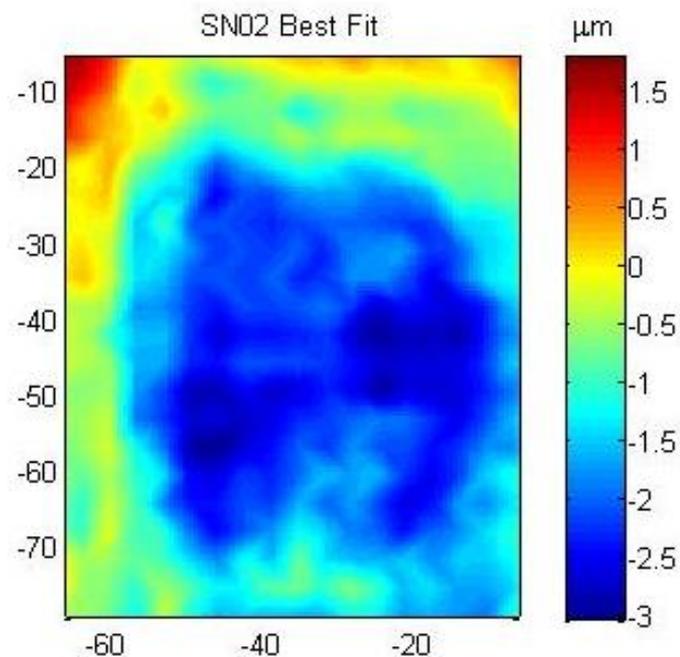
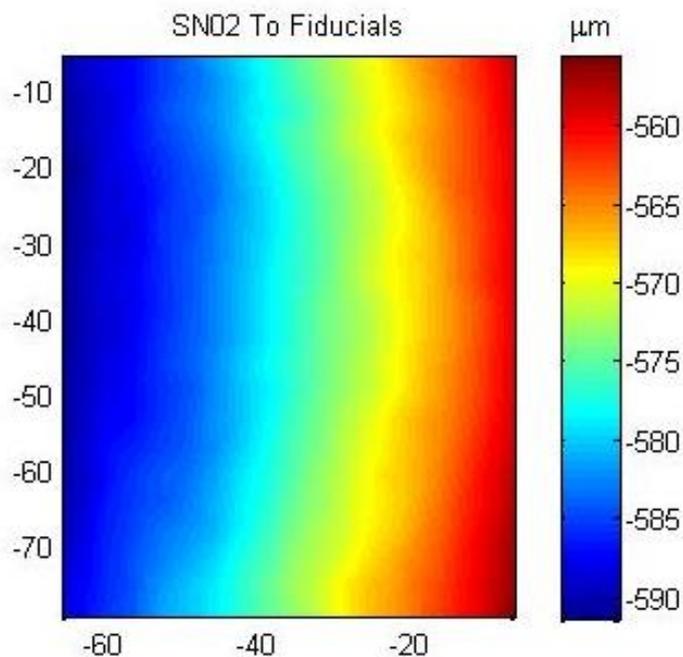
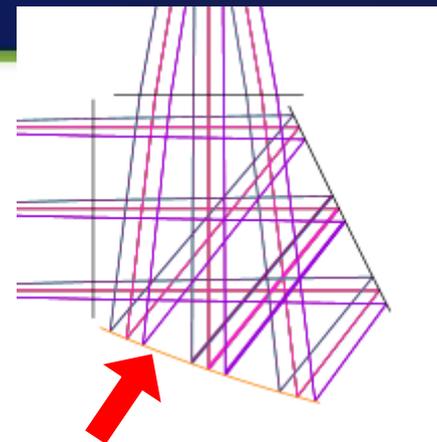


Multi Surface Freeform Monolithic Optic



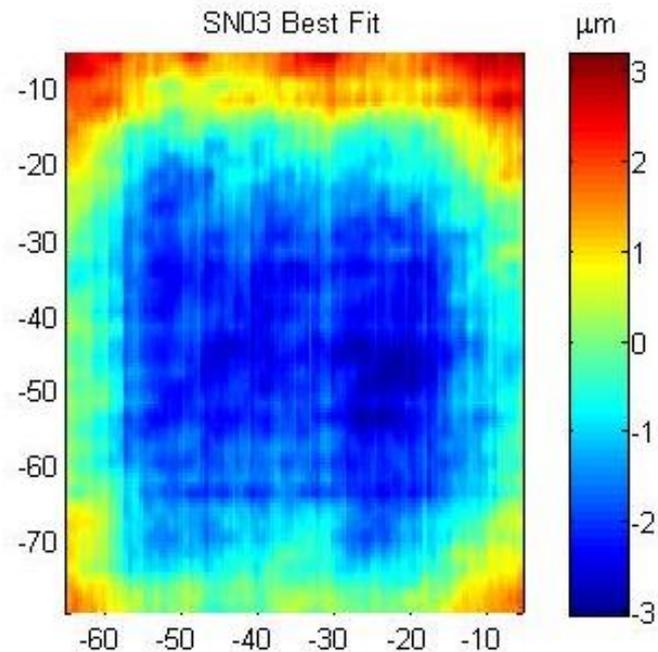
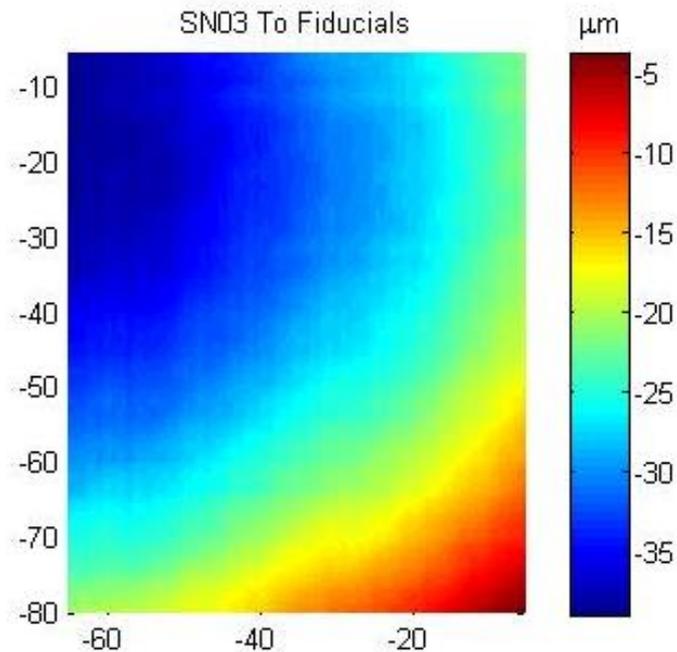
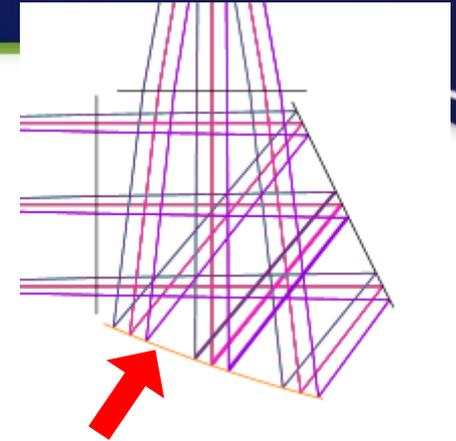
SN02: Freeform Surface 3 is finished

- Standard Quality
- Plano surfaces are complete and polished
- Freeform surface 3 is complete
- Best-Fit PV is $4.8\ \mu\text{m}$
- Overall surface is thin, $0.57\ \text{mm}$
- About $35\ \mu\text{m}$ tilt



SN03: Freeform Surface 3 is almost finished

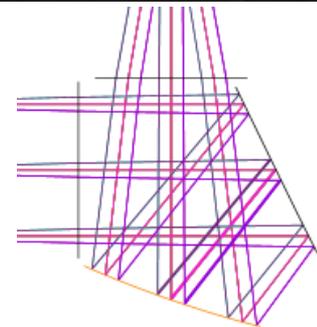
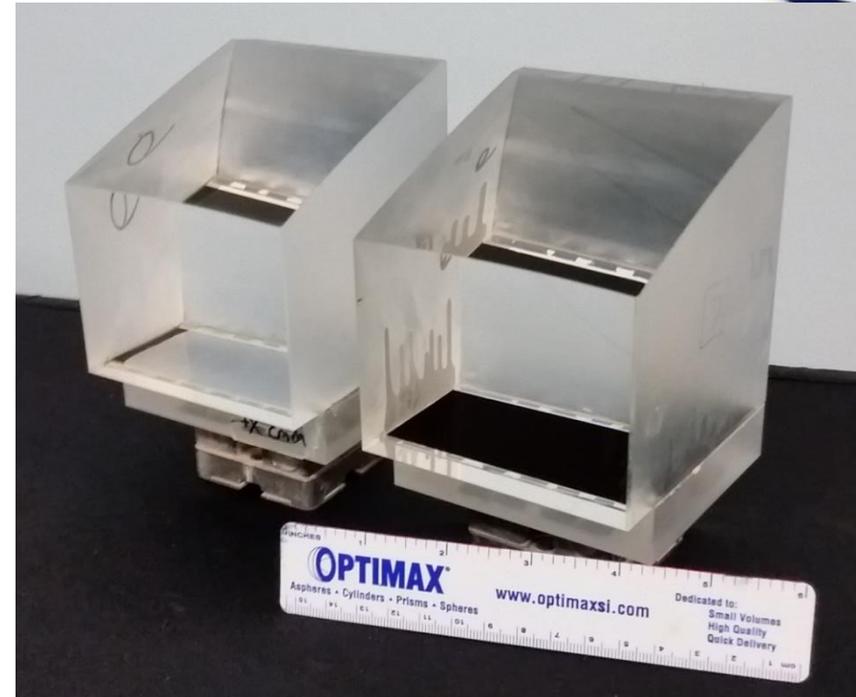
- High quality fused silica
- Plano surfaces are complete and polished
- Freeform surface 3 is probably now complete
- Best-Fit PV is $6.2\ \mu\text{m}$
- Within thickness tolerance
- About $35\ \mu\text{m}$ tilt



Multi Surface Freeform Monolithic Optic

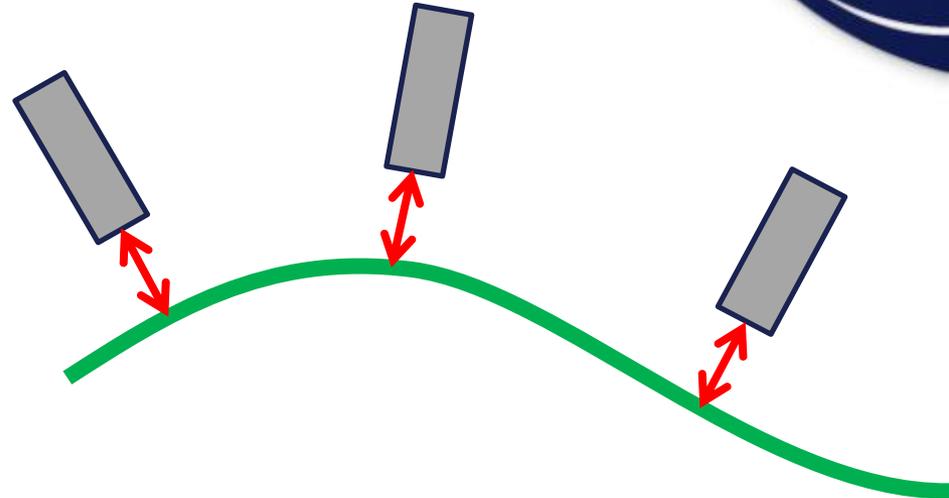
Next steps

- Polish freeform surface 2
 - Mirror coat freeforms
 - Test wavefront error and PSF
 - Figure correct plano surface(s) to improve wavefront error
-
- Coordinate system referencing is critical
 - Next versions will have tighter tolerances on the surface to surface error

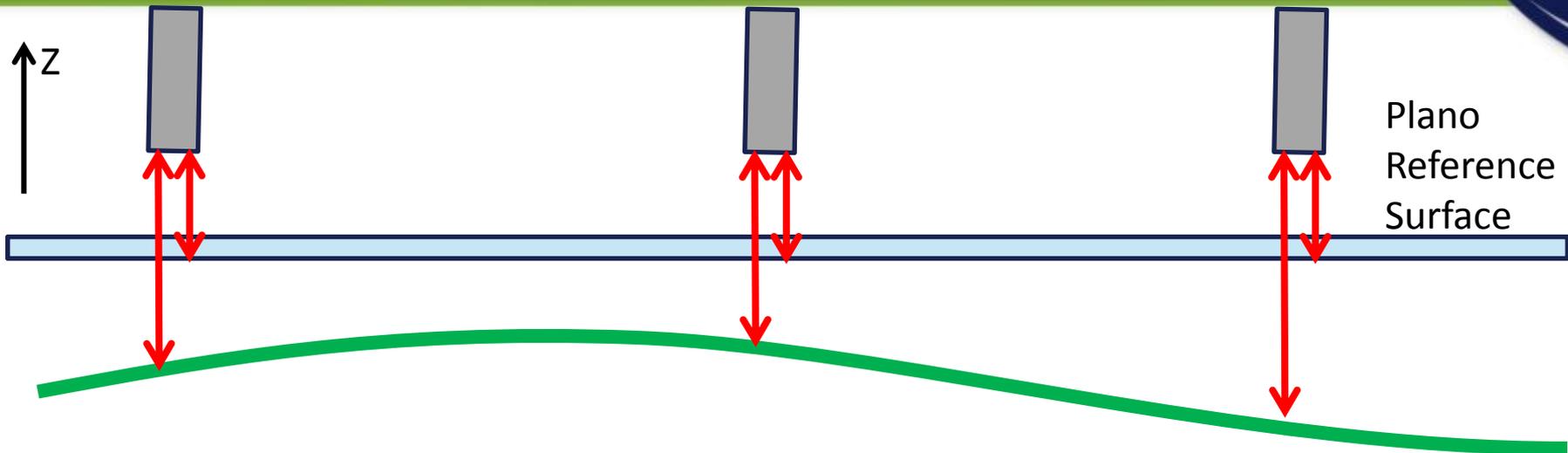


Development Project: Self Referencing Single Point Probing Surface Measurements

- Measurements of surfaces using single point polishing typically require movement in 5 degrees of freedom
- Leads to difficulties in separating error motions and surface figure error
- Using a reference surface can reduce this error

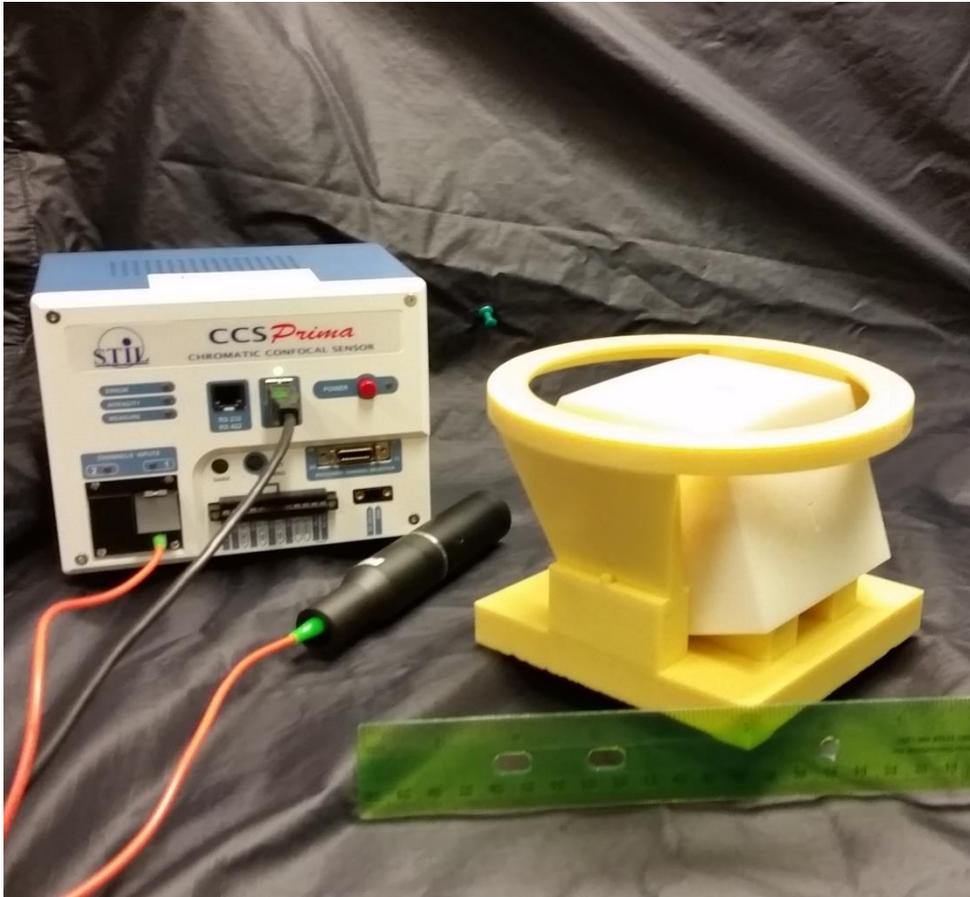


Development Project: Single Point Probing Surface Measurements

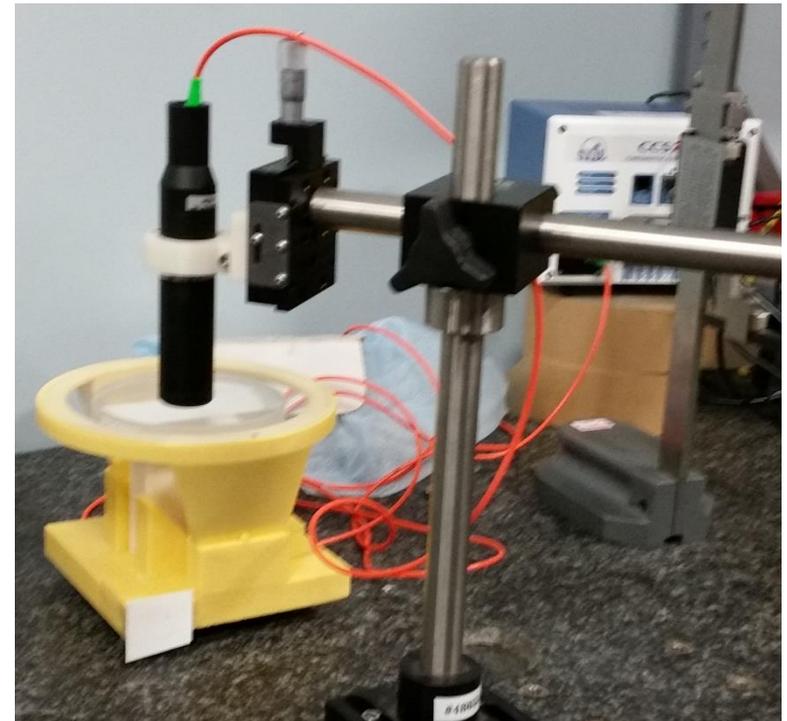


- Chromatic confocal probe can detect multiple surfaces
- Measures distance between reference surface and test optic
- Eliminates errors due to error motions in the Z direction
- Errors in x,y are still a factor, but this is much less critical
- Significant limitations for part's sag and slope
- Both monolithic freeform surfaces will be measurable with our setup

Initial Measurements are just being started

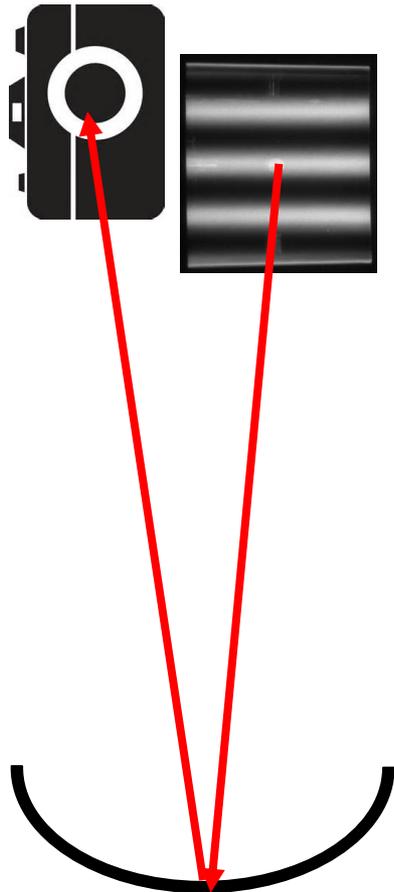


Wafer calibration with an optical flat



Development Project: Fringe Reflection Deflectometry Measurement

We set out to answer the applicability of this technology to in-process inspection of freeform optics.



- Used in automotive glass and body parts
- More limited basis for telescope mirrors, solar concentrators
- Imaging system views pattern reflected from or projected on the test surface
- Distortion or "deflection" of the pattern is used to derive surface slopes.
- To test:
 - Materials
 - Ground/Polished
 - Mirror Coated/Uncoated
 - Max slope
 - Part Fixturing
 - Apertures

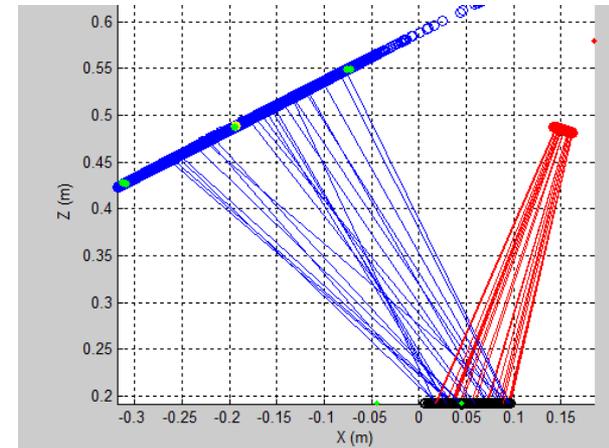


Measured position of components to build geometric model



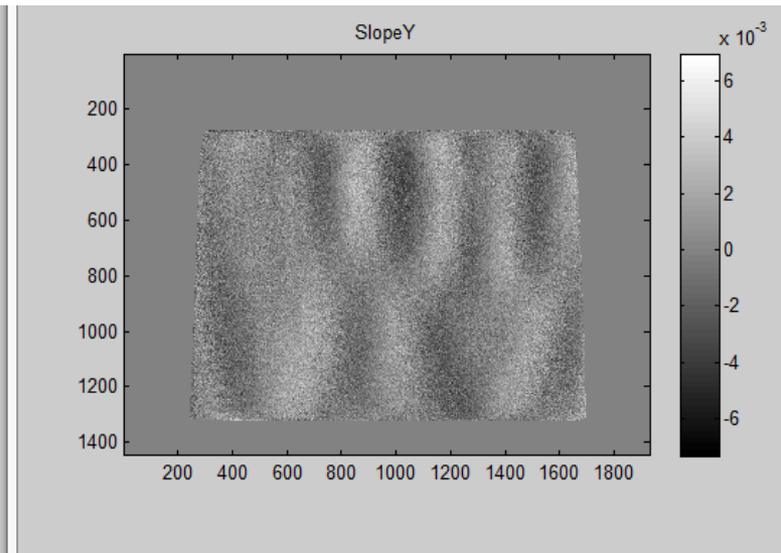
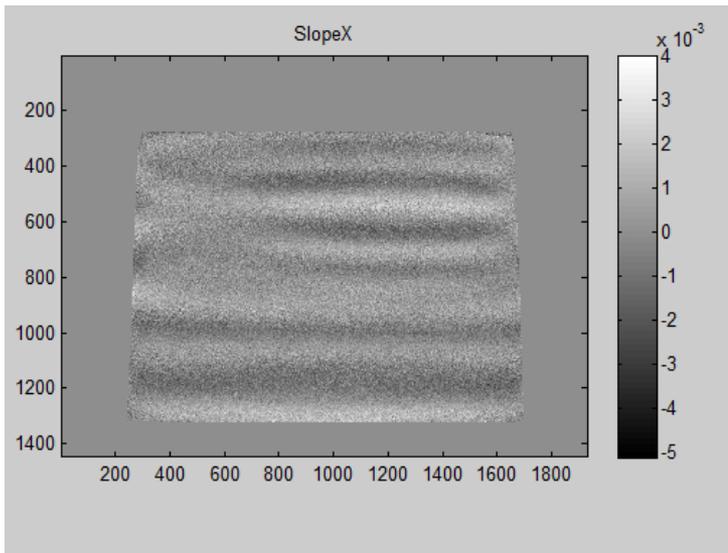
The geometry of the camera, part and target must be calibrated in 6 DOF.

Deflectometry can either give relative slope or absolute shape, depending on how well the geometry is calibrated. To determine absolute surface shape a world coordinate origin, or a measurement between target and part is needed.



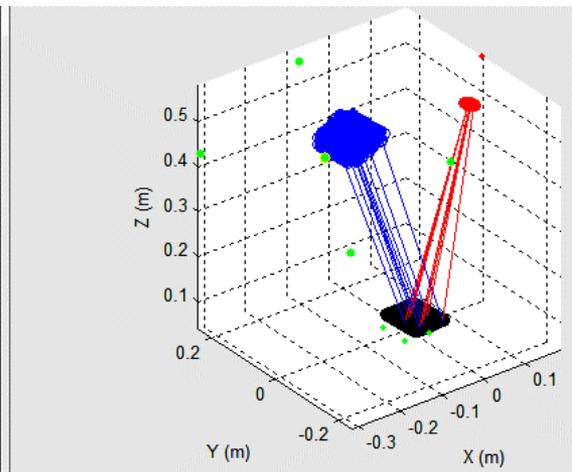
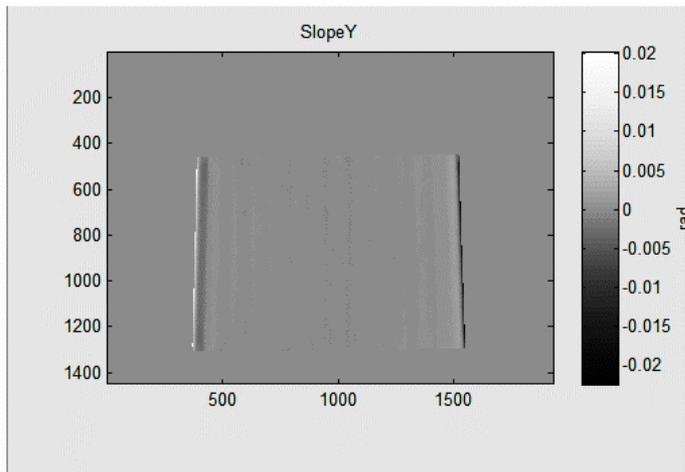
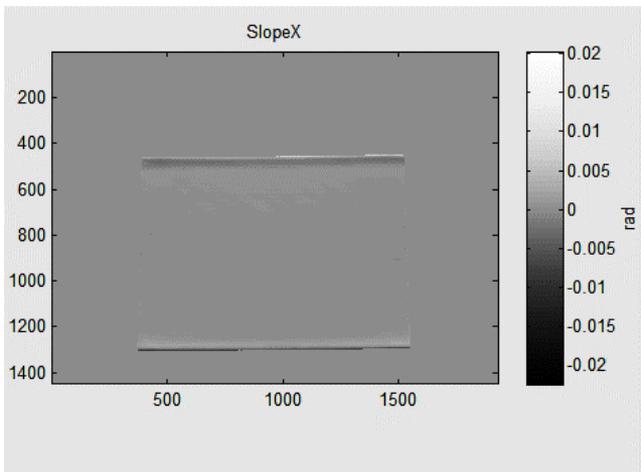
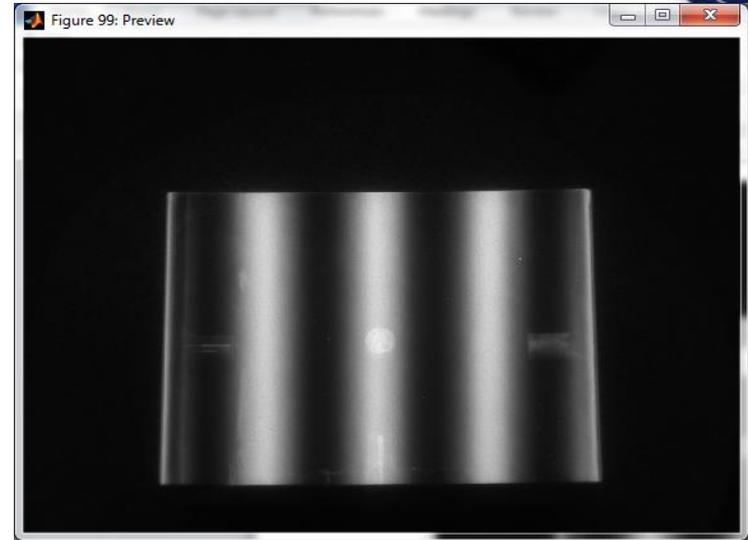
Currently limited to milliradians, desired is microradians

- Systematic noise in the milliradian range
- Source of waviness is probably Moire patterns between the LCD screen and the camera pixels
- Hardware improvement is upcoming in the near future
- Still possibilities for system subtraction

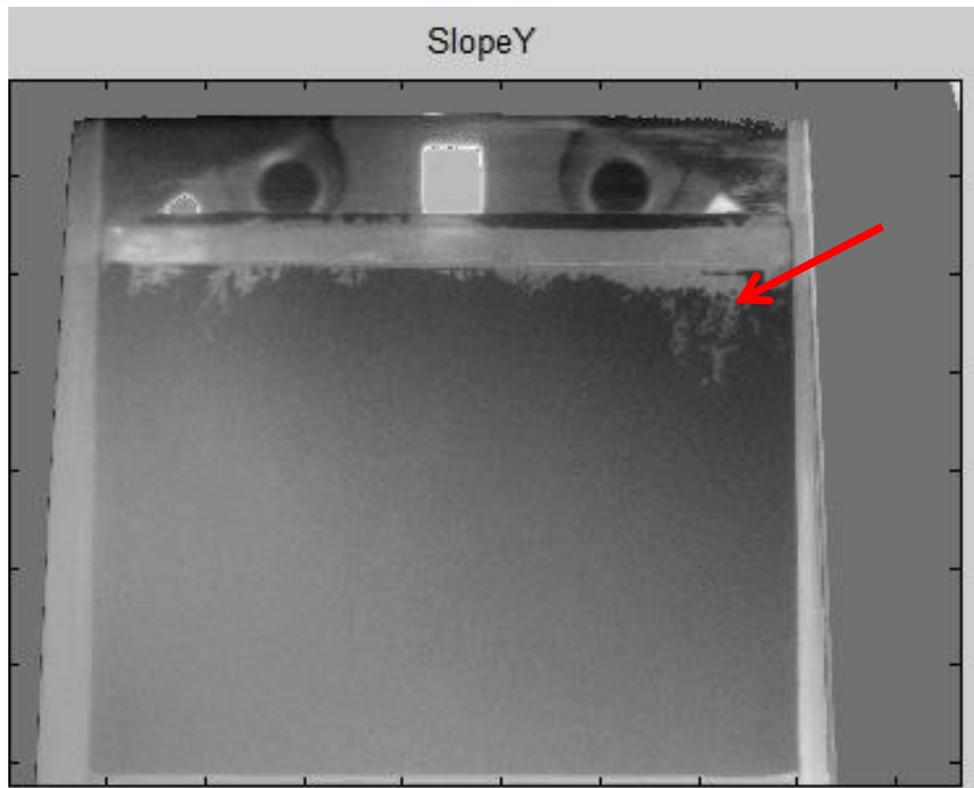


Measurement of Freeform Surface shows rolled edges

- Even with the waviness noise, the rolled edges were seen
- Internal mounting features caused some errors



Very Sensitive to Part Condition



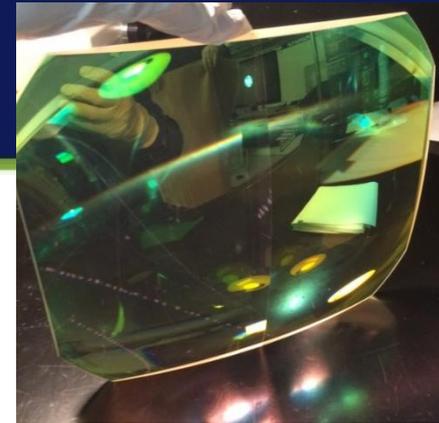
For a glass substrate, all non-measured surfaces must be painted black

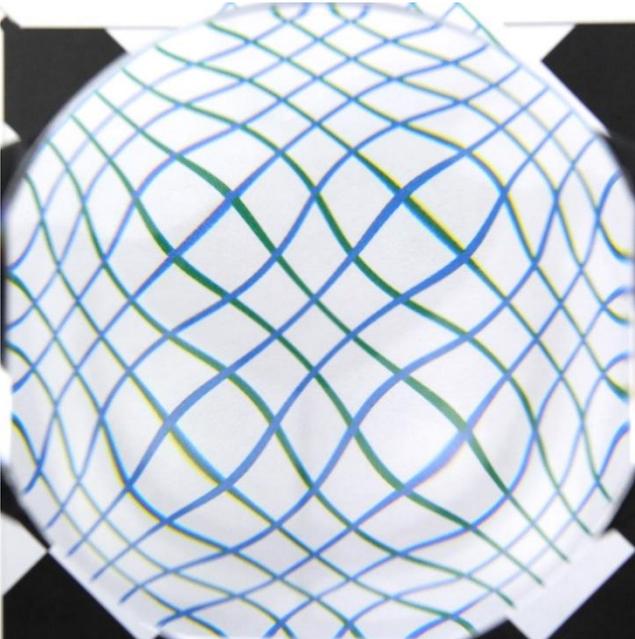
Mounting components can cause errors

We are also looking at commercial systems to see if they are truly applicable in a optical manufacturing shop

Summary

- Freeform optics are a commercial product offering at Optimax
- Development projects:
 - Manufacturing Monolithic Freeform Optics
 - Freeform Measurements:
 - Self Referencing Referenced Single Point Probing
 - Fringe Reflection Deflectometry





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